

TITLE OF INVENTION: A TEST SOCKET FOR AND METHOD OF TESTING
ELECTRONIC COMPONENTS, IN PARTICULAR HIGH-POWER SEMICONDUCTOR
COMPONENTS

5 ABSTRACT

A test socket for and a method of testing electronic components, in particular high-power semiconductor components comprise: a plurality of contact elements, being adapted to contact to the electronic component; a holder
10 block for holding and arranging the plurality of contact elements, wherein each contact element of the plurality of contact elements comprises at least one conductive surface portion; wherein the holder block comprises a plurality of electrically conductive support sections, for supporting the conductive surface portions of the plurality of contact elements, wherein the plurality of support
15 sections, makes electrical contact to the plurality of conductive surface portions by supporting the conductive surface portions, and wherein the holder block at least partially transmits a test signal.

(Fig. 1)

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